

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Hiroyuki ENOMOTO et al.

Appln. No.

Filed: HERewith

For: THE METHOD OF PRODUCING A SEMICONDUCTOR INTEGRATED  
CIRCUIT DEVICE AND THE SEMICONDUCTOR INTEGRATED  
CIRCUIT DEVICE

\* \* \*

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Without any assertion of materiality or prior art effect, Applicants wish to make record the documents cited in predecessor Application Nos. 10/256,027 filed September 27, 2002 and 10/036,449 filed January 7, 2002, whether cited by Applicants or by the Patent Office. The documents are listed on the attached Form-1449 as Documents AA-AJ on sheet 1 and AA\*-AB\* on sheet 2.

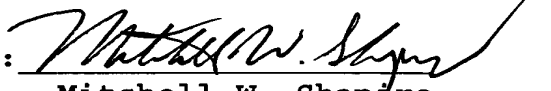
Applicants also wish to make of record Documents AK-AL  
on sheet 1 and AC\* on sheet 2 (copies provided herewith).

Respectfully submitted,

MWS:jab

Miles & Stockbridge P.C.  
1751 Pinnacle Drive, Suite 500  
McLean, Virginia 22102-3833  
(703) 903-9000

By:



Mitchell W. Shapiro  
Reg. No. 31,568

July 25, 2003

<b>FORM PTO-1449</b>				Atty. Docket No. <b>XA-9604B</b>		Appln. No.	
<b>LIST OF DOCUMENTS CITED BY APPLICANT</b>							
				Applicant <b>Hiroyuki ENOMOTO et al.</b>			
				Filing Date <b>HEREWITH</b>		Group	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA	5,817,562	10/06/98	CHANG et al.	438	305	
	AB	5,942,803	08/24/99	SHIM et al.	257	774	
	AC	6,037,211	03/14/00	JENG et al.	438	253	
	AD	6,136,716	10/24/00	TU	438	694	
	AE	6,300,238	10/09/01	LEE et al.	438	624	
	AF	6,037,228	03/2000	HSU	438	279	
	AG	6,228,731	05/2001	LIAW et al.	438	303	
	AH	6,335,279	01/2002	JUNG et al.	438	666	
<b>FOREIGN PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AI	11-135781	05/21/99	JAPAN			Abstract
	AJ	11-68064	03/09/99	JAPAN			Abstract
	AK	5-47720	2/26/93	JAPAN			Abstract
	AL	9-330976	12/22/97	JAPAN			Abstract
<b>OTHER</b> (including author, title, date, pertinent pages, etc.)							
	AM						
	AN						
	AO						
Examiner				Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							

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<b><u>LIST OF DOCUMENTS CITED BY APPLICANT</u></b>							
				<b>Applicant</b> <b>Hiroyuki ENOMOTO et al.</b>			
				<b>Filing Date</b> <b>HEREWITH</b>		<b>Group</b>	
<b>U.S. PATENT DOCUMENTS</b>							
<b>Examiner Initial</b>		<b>Document Number</b>	<b>Date</b>	<b>Name</b>	<b>Class</b>	<b>Sub-class</b>	<b>Filing Date</b>
	AA*	6,501,140	12/2002	HONEYCUTT et al.	257	411	
	AB*	6,531,350	3/2003	SATOH et al.	438	197	
	AC*	6,555,861	4/29/03	YAMADA et al.	257	298	
	AD						
	AE						
	AF						
	AG						
	AH						
<b>FOREIGN PATENT DOCUMENTS</b>							
<b>Examiner Initial</b>		<b>Document Number</b>	<b>Date</b>	<b>Country</b>	<b>Class</b>	<b>Sub-class</b>	<b>Translation</b>
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	AO						
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